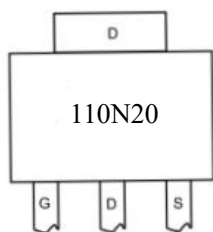
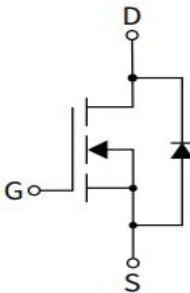




Features ➤ Split Gate Trench MOSFET technology ➤ Excellent package for heat dissipation ➤ High density cell design for low $R_{DS(ON)}$	<i>Bvdss</i>	<i>Rdson</i>	<i>ID</i>
	200V	8.9mΩ	120A
	Application ➤ DC-DC Converters ➤ Power management function ➤ Synchronous-rectification applications		



Package		
		
Marking and pin assignment	TO220 top view	Schematic diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Quantity
110N20	S110N20T	TO220	50

Absolute Maximum Ratings (T_C=25°C unless otherwise specified)

Parameter		Symbol	Value	Unit
Drain-Source Voltage		V _{DS}	200	V
Gate-Source Voltage		V _{GS}	±20	V
Continuous Drain Current ¹	T _C =25°C	I _D	120	A
	T _C =100°C	I _D	80	A
Pulsed Drain Current ²		I _{DM}	458	A
Single Pulsed Avalanche Energy ³		E _{AS}	320	mJ
Power Dissipation ⁴		P _D	355	W
Junction Temperature Range		T _J	-55 ~ 150	°C
Storage Temperature Range		T _{STG}	-55 ~ 150	°C

Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-ambient	R _{θJA}	45	°C/W
Thermal Resistance Junction-Case	R _{θJC}	0.42	°C/W



Ordering Information

Ordering Number	Package	Pin Assignment			Packing
Halogen Free		G	D	S	
HLS110N20T	TO220	1	2	3	Tube

Electrical Characteristics ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain to Source Breakdown Voltage	V_{DSS}	$I_{\text{D}}=250\mu\text{A}$, $V_{\text{GS}}=0\text{V}$	200	-	-	V
Drain-Source Leakage Current	I_{DSS}	$V_{\text{DS}}=200\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=25^{\circ}\text{C}$	-	-	1	μA
		$V_{\text{DS}}=80\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=100^{\circ}\text{C}$	-	-	100	μA
Gate to Source Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{GS}}=V_{\text{DS}}$, $I_{\text{D}}=250\mu\text{A}$	2	3	4	V
Static Drain-Source On-Resistance ²	$R_{\text{DS(on)}}$	$V_{\text{GS}}=10\text{V}$, $I_{\text{D}}=60\text{A}$	-	8.9	10.8	m Ω
Forward Transconductance	g_{fs}	$V_{\text{DS}}=5\text{V}$, $I_{\text{D}}=60\text{A}$	-	104	-	S
Diode Forward Voltage ²	V_{SD}	$I_{\text{S}}=60\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	1.3	V
Diode Continuous Current ^{1,4}	I_{S}	$V_{\text{G}}=V_{\text{D}}=0\text{V}$, Force Current	-	--	120	A
Input Capacitance	C_{iss}	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=100\text{V}$, $f=1\text{MHz}$	-	5270	-	pF
Output Capacitance	C_{oss}		-	460	-	pF
Reverse Transfer Capacitance	C_{rss}		-	24	-	pF
Gate Resistance	R_{g}	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=0\text{V}$, $f=1\text{MHz}$	-	3.5	-	Ω
Turn-ON Delay Time	$t_{\text{d(on)}}$	$V_{\text{GS}}=10\text{V}$, $V_{\text{DD}}=100\text{V}$, $R_{\text{G}}=2.7$, $I_{\text{D}}=60\text{A}$	-	35	-	ns
Rise Time	t_{r}		-	111	-	
Turn-OFF Delay Time	$t_{\text{d(off)}}$		-	84	-	
Fall Time	t_{f}		-	112	-	
Total Gate Charge@ $V_{\text{GS}}=10\text{V}$	Q_{g}	$V_{\text{GS}}=10\text{V}$, $V_{\text{DS}}=100\text{V}$, $I_{\text{D}}=60\text{A}$	-	74	-	nC
Gate Source Charge	Q_{gs}		-	30	-	
Gate Drain Charge	Q_{gd}		-	16	-	
Body Diode Reverse Recovery Time	T_{rr}	$\text{IF}=17\text{A}$, $\text{dIF/dt}=100\text{A/s}$	-	151	-	ns
Body Diode Reverse Recovery Charge	Q_{rr}		-	779	-	nC

Notes:

1. Repetitive rating, pulse width limited by junction temperature $T_{\text{J(MAX)}}=150^{\circ}\text{C}$
2. The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=100\text{V}$, $V_{\text{GS}}=10\text{V}$, $L=0.5\text{mH}$, $I_{\text{AS}}=36\text{A}$.
3. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.



Typical Performance Characteristics

Fig 1: Output Characteristics

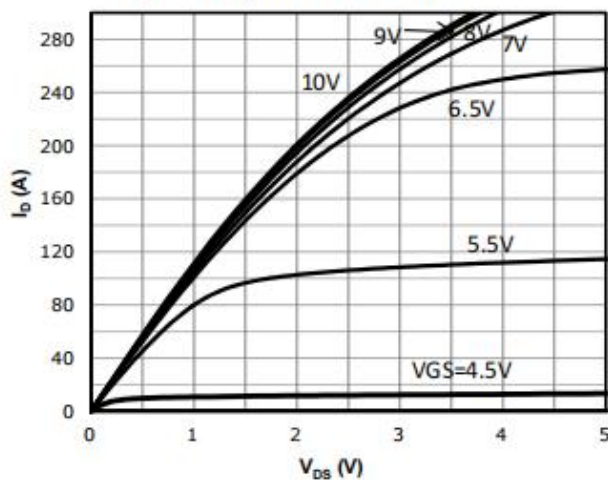


Fig 2: Transfer Characteristics

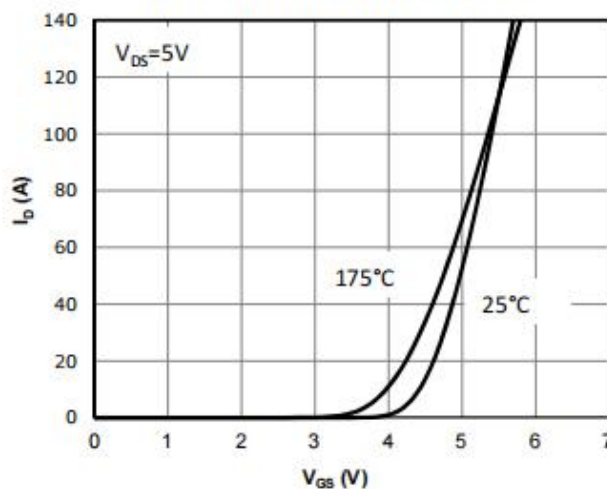


Fig 3: R_{DS(on)} vs Drain Current and Gate Voltage

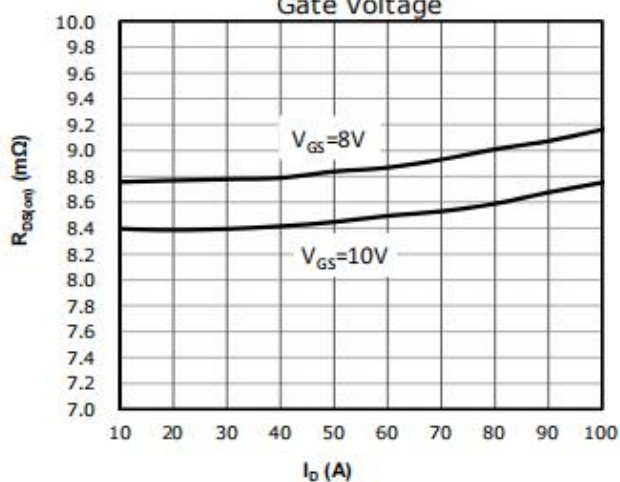


Fig 4: R_{DS(on)} vs Gate Voltage

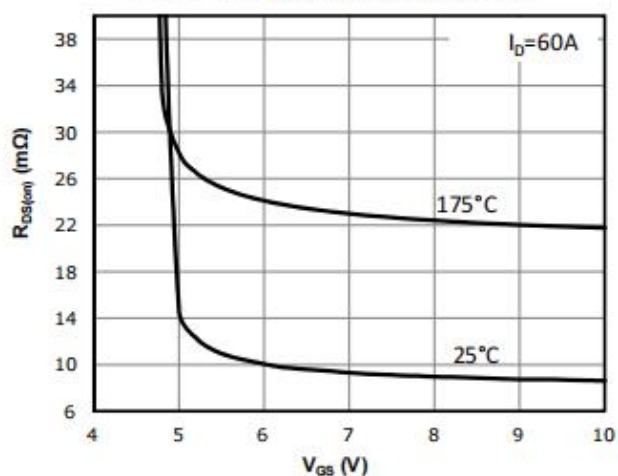


Fig 5: R_{DS(on)} vs. Temperature

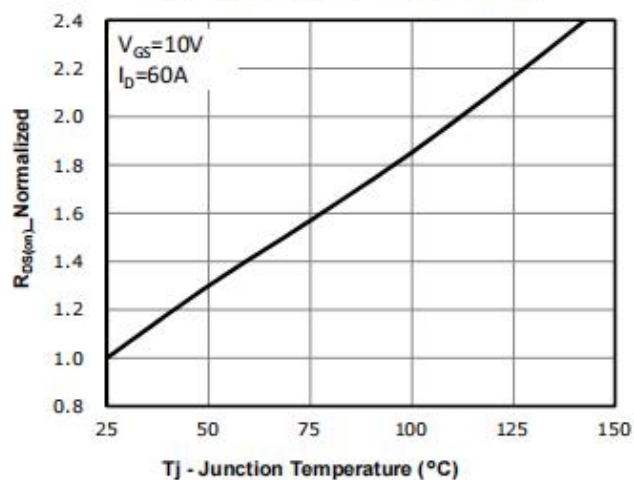


Fig 6: Capacitance Characteristics

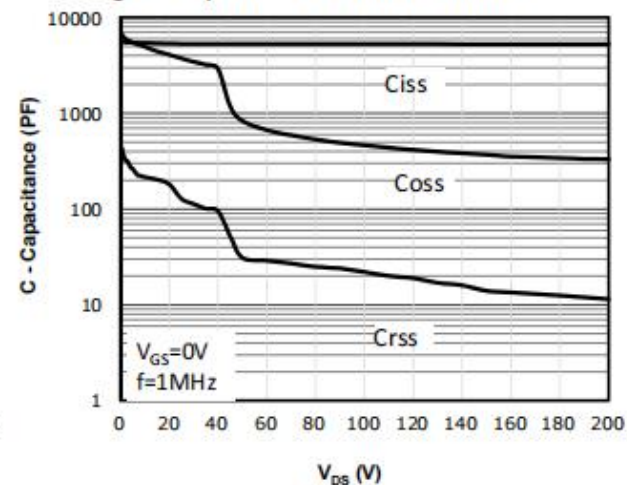


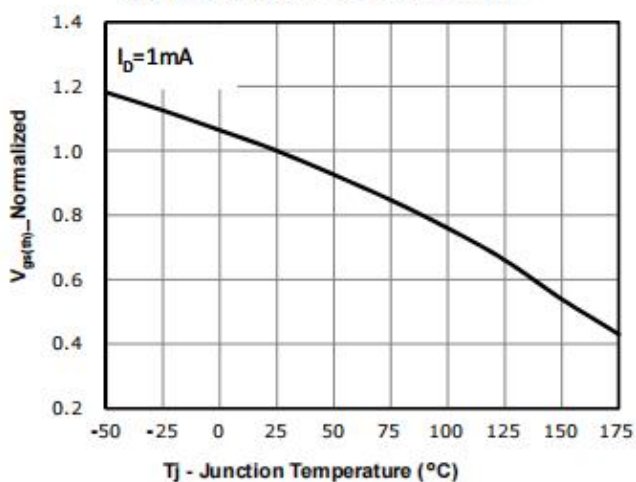
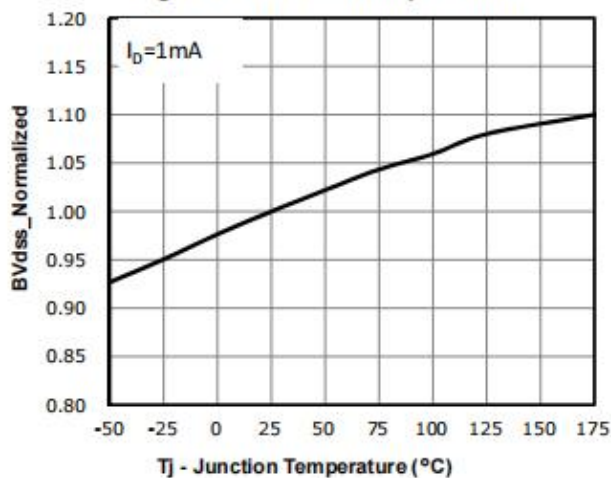
Fig 7: $V_{gs(th)}$ vs. TemperatureFig 8: BV_{dss} vs. Temperature

Fig 9: Gate Charge Characteristics

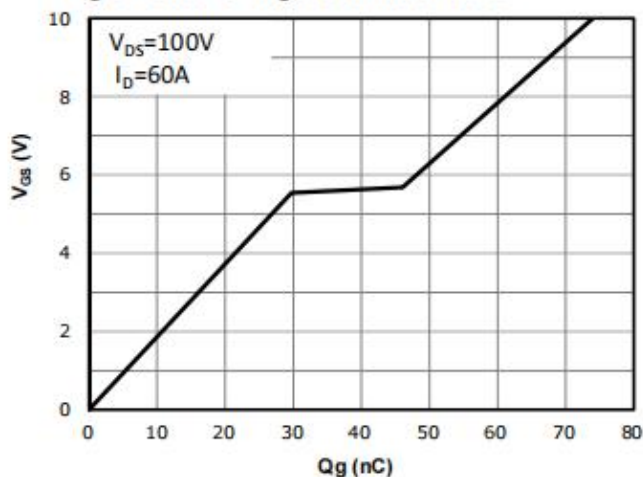


Fig 10: Body-diode Forward Characteristics

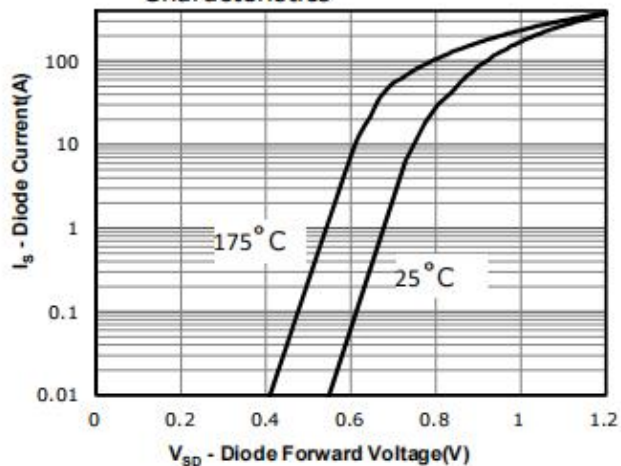


Fig 11: Power Dissipation

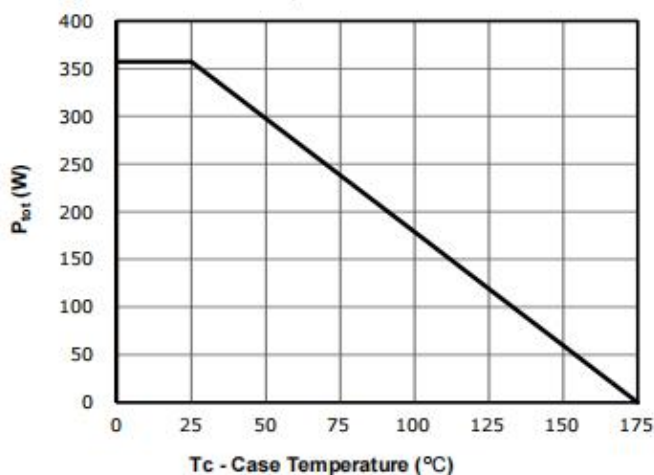


Fig 12: Drain Current Derating

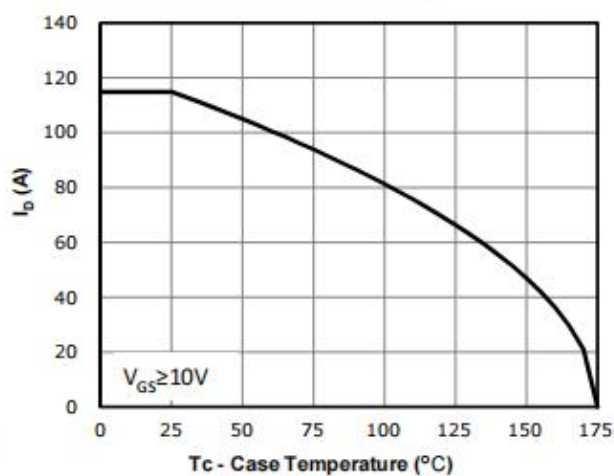




Fig 13: Safe Operating Area

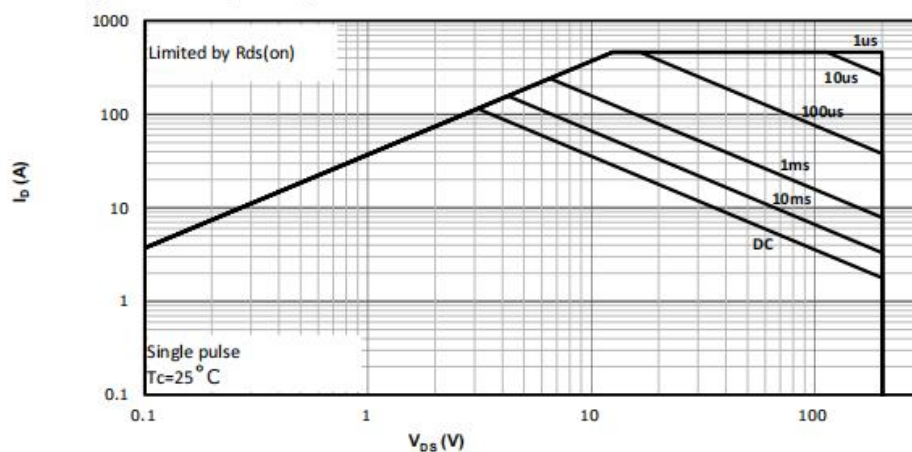
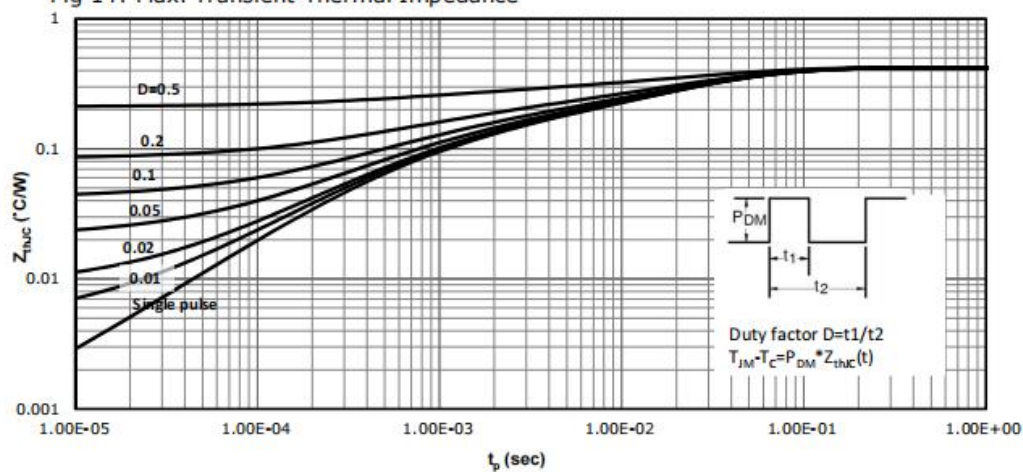


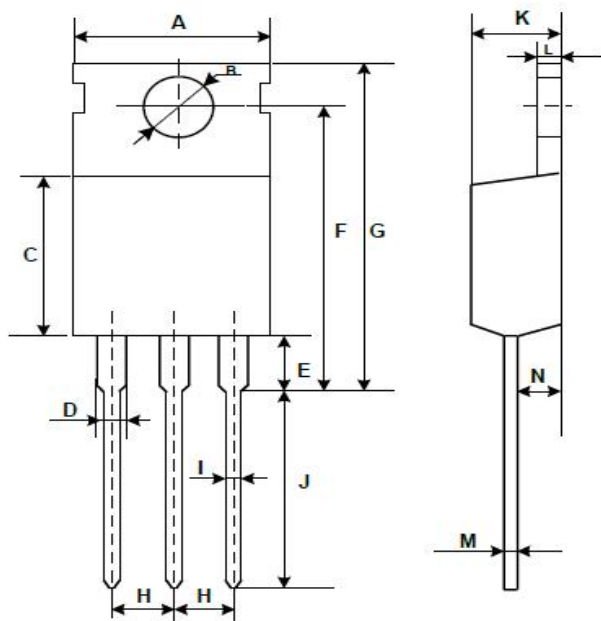
Fig 14: Max. Transient Thermal Impedance





Package Dimensions TO220

COMMON DIMENSIONS



SYMBOL	MM	
	MIN	MAX
A	9.70	10.30
B	3.40	3.80
C	8.80	9.40
D	1.17	1.47
E	2.60	3.50
F	15.10	16.70
G	19.55MAX	
H	2.54REF	
I	0.70	0.95
J	9.35	11.00
K	4.30	4.77
L	1.20	1.45
M	0.40	0.65
N	2.20	2.60



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